

## IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re application of: KINNEY et al.

Attorney Docket No.: UNTYP025

Application No.: 10/605,757

Examiner: not yet assigned

Filed: October 23, 2003

Group: 2818

Title: MULTI-LAYER CONDUCTIVE MEMORY

Confirmation No.: 2756

**DEVICE** 

CERTIFICATE OF MAILING

I hereby certify that this correspondence is being deposited with the U.S. Postal Service with sufficient postage as first-class mail in an envelope addressed to the Commissioner for Patents, P.O. Box 1450 Alexandria, VA 22313-1450 on JUNE 2004.

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## INFORMATION DISCLOSURE STATEMENT 37 CFR §§1.56 AND 1.97(b)

Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

Dear Sir/Ms.:

The references listed in the attached PTO Form 1449, copies of which are attached, may be material to examination of the above-identified patent application. Applicants submit these references in compliance with their duty of disclosure pursuant to 37 CFR §§1.56 and 1.97. The Examiner is requested to make these references of official record in this application.

This Information Disclosure Statement is not to be construed as a representation that a search has been made, that additional information material to the examination of this application does not exist, or that these references indeed constitute prior art.

This Information Disclosure Statement is: (i) filed within three (3) months of the filing date of the above-referenced application, (ii) believed to be filed before the mailing date of a first Office Action on the merits, or (iii) believed to be filed before the mailing of a first Office Action after the filing of a Request for Continued Examination under §1.114. Accordingly, it is believed that no fees are due in connection with the filing of this Information Disclosure Statement. However, if it is determined that any fees are due, the Commissioner is hereby authorized to charge such fees to Deposit Account 500388 (Order No. UNTYP025).

Respectfully submitted,

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1449 (Modified)

**Information Disclosure Statement By Applicant**  Atty Docket No. UNTYP025

Application No.: **10/605,757** 

Applicant:

RINERSON et al.

(Use Several Sheets if Necessary)

Filing Date **10/23/2003** 

Group **2818** 

## **U.S. Patent Documents**

Examine	er						Sub-	Filing
Initial	:	No.	Patent No.	Date	Patentee	Class	class	Date
		<b>A</b> 1	6,204,139	3/2001	Liu et al.			

Foreign Patent or Published Foreign Patent Application

Examiner		Document	Publication	Country or		Sub-	Trans	lation
Initial	No.	No.	Date	Patent Office	Class	class	Yes	No
	B1							

## **Other Documents**

Examiner					
Initial	No.	Author, Title, Date, Place (e.g. Journal) of Publication			
	C1	Beck et al., "Reproducible switching effect in thin oxide films for memory			
		applications", 2000, Applied Physics Letters, Vol. 77, No. 1, pp. 139-141.			
	C2	Betsuyaku et al., "Material Design for the Fabrication of p-type SrTiO <sub>3</sub> ", 2001, Jpn. J.			
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	C3	Gerstner et al., "Nonvolatile memory effects in nitrogen doped tetrahedral amorphous			
		carbon thin films", 1998, Journal of Applied Physics, Vol. 84, No. 10, pp. 5647-5651.			
	C4	Kim et al., "Leakage Current Properties of (Ba, Sr)TiO <sub>3</sub> Films on Doped (Ba,			
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	C5	Liu et al., "Electric-pulse-induced reversible resistance change effect in			
		magnetoresistive films", 2000, Applied Physics Letters, Vol. 76, No. 19, pp. 2749-			
		2571.			
	C6	Simmons et al., "New conduction and reversible memory phenomena in thin			
	ļ	insulating films", 1967, Proc. Roy. Soc. A., Vol. 301, pp. 77-102.			
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	C9	Watanabe et al., "Current-driven insulator-conductor transition and nonvolatile			
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	C11	Watanabe et al., "Highly Resolved Conduction Properties of			
		Ferroelectric/Semiconductor Diodes Exhibiting Memory Effect", 1998, Journal of the			
<del> </del>	C12	Korean Physical Society, Vol. 32, pp. S1361-S1364.			
	C12	Zhuang et al., "Novell Colossal Magnetoresistive Thin Film Nonvolatile Resistance			
Examiner	<u> </u>	Random Access Memory (RAM)", © 2002 IEEE, 0-7803-7463-X/02			
Exammer		Date Considered			
		testion considered Development and the state of the state			

Examiner: Initial citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.